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Advanced Deep Learning and Neural Network Technologies for Image Recognition

Guest Editors:

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Deadline for manuscript submissions:

closed (28 February 2022)

Message from the Guest Editors

The main aim of this Special Issue is to seek original contributions that address the above challenges or highlight emerging applications in image recognition. The topics of interest include but are not limited to:

- Robust recognition with perturbations;
- Explainable deep learning;
- Multimodal or multiview recognition;
- Weakly supervised learning;
- Self-supervision learning;
- Privacy-aware recognition;
- Data augmentation;
- Transfer learning and domain adaptation;
- Few/one shot learning;
- GANs for image recognition;
- Deepfake detection;
- Distance metric learning;
- Uncertainty estimation;
- Out-of-distribution detection;
- Activity and online learning;
- Advanced and novel biometrics systems;
- Practical and reliable medical image recognition











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Editor-in-Chief

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Message from the Editor-in-Chief

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